

STS20NHS3LL

N-CHANNEL 30 V - 0.0032 Ω - 20 A SO-8 STripFETTMIII MOSFET PLUS MONOLITHIC SCHOTTKY

PRELIMINARY DATA

Table 1: General Features

TYPE	V _{DSS} R _{DS(on)}		I _D
STS20NHS3LL	30V	< 0.004Ω	20A(1)

- TYPICAL R_{DS}(on) = 0.0032Ω @ 10V
- OPTIMAL R_{DS}(on) x Qg TRADE-OFF @ 4.5V
- REDUCED SWITCHING LOSSES
- REDUCED CONDUCTION LOSSES
- REDUCED DIODE RECOVERY LOSSES
- IMPROVED JUNCTION-CASE THERMAL RESISTANCE

DESCRIPTION

The **STS20NHS3LL** utilizes the latest advanced design rules of ST's proprietary STripFET[™] technology, and a proprietary process for integrating a monolithic Schottky diode. The new MOSFET is optimized for the most demanding synchronous switch function in DC-DC converter for Computer and Telecom.

APPLICATIONS

- DC-DC CONVERTERS FOR TELECOM AND NOTEBOOK CPU CORE
- SYNCHRONOUS RECTIFICATION

Figure 1: Package

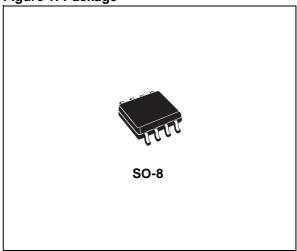


Figure 2: Internal Schematic Diagram

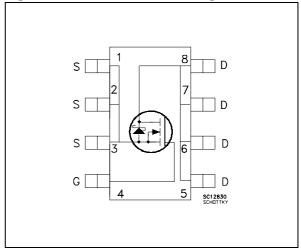


Table 2: Order Codes

SALES TYPE	MARKING	PACKAGE	PACKAGING
STS20NHS3LL	20HS3LL-	SO-8	TAPE & REEL

Table 3: Absolute Maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V
V _{GS}	Gate- source Voltage	± 18	V
I _{D(1)}	Drain Current (continuous) at T _C = 25°C	20	А
I _D	Drain Current (continuous) at T _C = 100°C	12.6	А
I _{DM} (2)	Drain Current (pulsed)	80	А
P _{tot}	Total Dissipation at T _C = 25°C	2.7	W

Table 4: Thermal Data

Ĭ	Rthj-amb (3)	Thermal Resistance Junction-ambient Max	47	°C/W
		Maximum Operating Junction Temperature	-55 to 150	°C
	T_{stg}	Storage Temperature	-55 to 150	°C

Table 5: Avalanche Characteristics

Symbol	Parameter	Max Value	Unit
I _{AV}	Not-Repetitive Avalanche Current (pulse width limited by T _j max)	12.5	А
E _{AS}	Single Pulse Avalanche Energy (starting $T_j = 25$ °C, $I_D = I_{AV}$, $V_{DD} = 24$ V)	1.3	J

ELECTRICAL CHARACTERISTICS (T_J =25°C UNLESS OTHERWISE SPECIFIED)

Table 6: On /Off

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 1$ mA, $V_{GS} = 0$	30			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{DS} = 24V			500	μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 18V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 1mA$	1		2.5	V
		V _{GS} = 10V, I _D = 10A V _{GS} = 4.5V, I _D = 10A		0.0032 0.004	0.004 0.0055	Ω

Table 7: Dynamic

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (4)	Forward Transconductance	V _{DS} =15V, I _D = 12A		30		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V$, $f = 1MHz$, $V_{GS} = 0$		3950 720 70		pF pF pF

ELECTRICAL CHARACTERISTICS (CONTINUED)

Table 8: Switching On

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$\begin{aligned} &V_{DD} = 15V, I_{D} = 10A \\ &R_{G} = 4.7\Omega \; , V_{GS} = 4.5V \\ &(see \; Figure \; 15) \end{aligned}$		TBD TBD		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} =15V, I _D =20A V _{GS} = 4.5V (see Figure 17)		27.5 7.9 8.7	37	nC nC nC

Table 9: Switching Off

Ī	Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
	$t_{d(off)} \ t_{f}$	Turn-off Delay Time Fall Time	$V_{DD} = 15V, I_D = 10A$ $R_{G} = 4.7\Omega, V_{GS} = 4.5V$ (see Figure 15)		TBD TBD		ns ns

Table 10: Source Drain Diode

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM}	Source-drain Current Source-drain Current (pulsed)				20 80	A A
V _{SD} (4)	Forward On Voltage	I _{SD} = 10A ,V _{GS} = 0			0.7	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 10A$, di/dt = 100A/ μ s $V_{DD} = 25V$, $T_j = 150$ °C (see Figure 16)		1.9	26 25	ns nC A

- Notes:
 1. This value is rated according to Rthj-pcb
 2. Pulse width limited by safe operating area
 3. When mounted on FR-4 board with 1 inch² pad, 2 oz of Cu and t < 10sec
 4. Pulsed: pulse duration = 300µs, duty cycle 1.5%

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Figure 3: Safe Operating Area

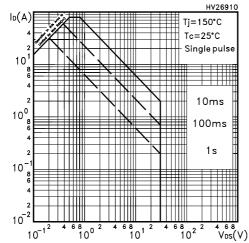


Figure 4: Output Characteristics

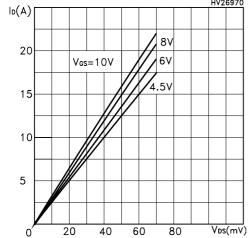


Figure 5: Transconductance

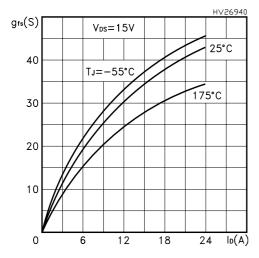


Figure 6: Thermal Impedance

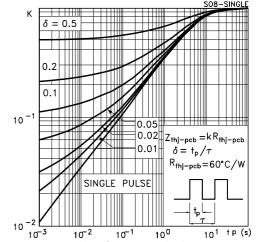


Figure 7: Transfer Characteristics

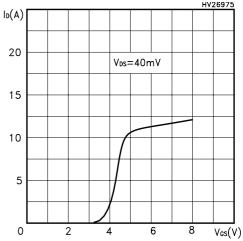


Figure 8: Static Drain-source On Resistance

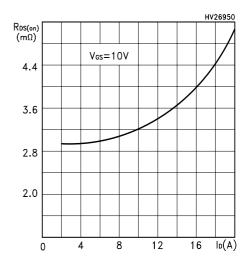


Figure 9: Gate Charge vs Gate-source Voltage

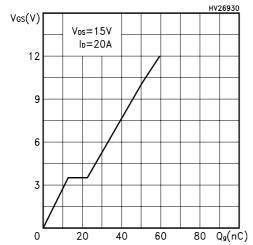


Figure 10: Normalized Gate Thereshold Voltage vs Temperature

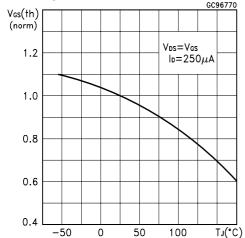


Figure 11: Normalized On Resistance vs Temperature

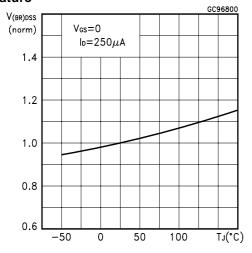


Figure 12: Capacitance Variations

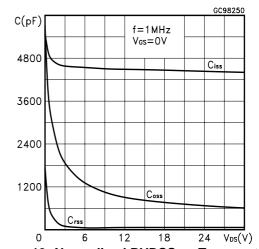


Figure 13: Normalized BVDSS vs Temperature

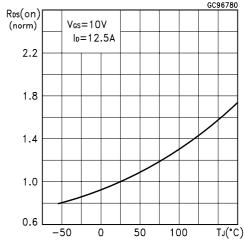


Figure 14: Source-Drain Diode Forward Characteristics

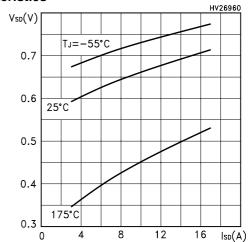


Figure 15: Switching Times Test Circuit For Resistive Load

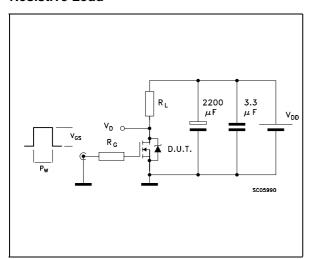


Figure 16: Test Circuit For Diode Recovery Times

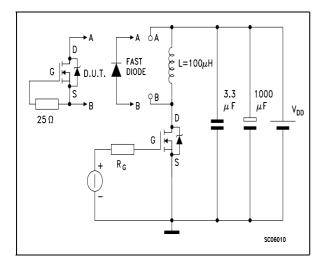
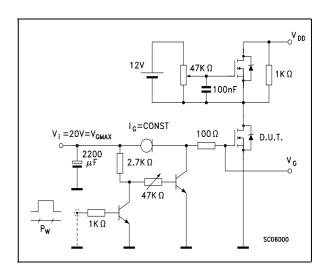
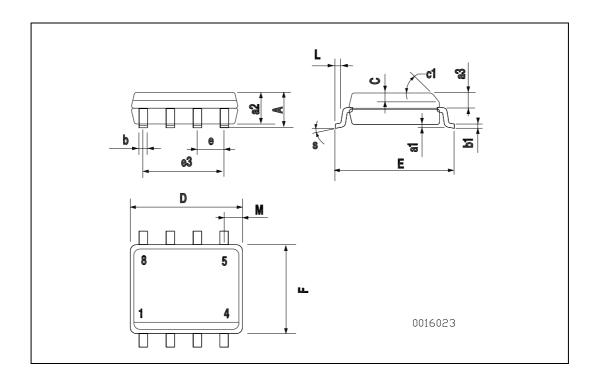


Figure 17: Gate Charge Test Circuit



SO-8 MECHANICAL DATA

DIM		mm.			inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α			1.75			0.068
a1	0.1		0.25	0.003		0.009
a2			1.65			0.064
a3	0.65		0.85	0.025		0.033
b	0.35		0.48	0.013		0.018
b1	0.19		0.25	0.007		0.010
С	0.25		0.5	0.010		0.019
c1			45	(typ.)		
D	4.8		5.0	0.188		0.196
Е	5.8		6.2	0.228		0.244
е		1.27			0.050	
e3		3.81			0.150	
F	3.8		4.0	0.14		0.157
L	0.4		1.27	0.015		0.050
М			0.6			0.023
S		8 (max.)				



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Table 11: Revision History

Date	Revision	Description of Changes
24-May-2005	1	First release
19-Dec-2005	2	Inserted curves

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